SHORT PROGRAMME

INTERNATIONAL METROLOGY CONGRESS

CIM2027

NEW HORIZONS IN METROLOGY

15 - 18 MARCH · LYON · FRANCE

ORGANISED BY CFM

www.cim-metrology.org

HOSTED AT GLOBAL INDUSTRIE

EDITO



Frédéric Barbaresco

THALES · France
CIM2027 co-chair

In an industrial world in which performance, technological sovereignty and risk management have become decisive imperatives, metrology should be regarded as an infrastructure underpinning innovation, reliability and trust.

The ability to measure with ever greater accuracy, speed and traceability has become a strategic industrial concern. Metrology therefore plays a pivotal role in enabling emerging technologies, providing the means to characterize their performance and master their industrialization.

Quantum technologies provide an illustration of this evolution. The characterization of quantum technologies is opening a new frontier for metrology to quantify the physical quality of devices, but also to assess their effective performance in addressing industrial applications.

Artificial intelligence is also profoundly transforming metrological practice. It offers unprecedented capabilities for exploiting vast volumes of data, enhancing anomaly detection, developing more sophisticated measurement models.

The CIM conference will therefore provide a privileged forum for dialogue between science and industry, helping to shape the measurement methodologies that will enable tomorrow's technologies to become the industrial solutions of today.



Philippe Richard

METAS · Switzerland
CIM2027 co-chair

In an increasingly data-driven world, having confidence in measurements is more important than ever. Whether it is supporting industrial innovation, scientific discovery, healthcare, energy systems or digital technologies, decisions ultimately depend on the quality and reliability of the results of measurements.

Two concepts lie at the heart of this: uncertainty of measurement and metrological traceability. Uncertainty in measurements provides a quantitative assessment of the quality of a result, while traceability establishes a direct link to recognized references through an unbroken chain of comparisons. Together, these concepts transform measurements into trusted information that can be shared and compared worldwide.

This confidence also hinges on international cooperation. By using SI Units, facilitating comparisons and promoting mutual recognition, the global metrology community ensures that measurements performed worldwide remain reliable and comparable.

As technologies become increasingly complex and interconnected, the importance of these foundations grows.

We look forward to welcoming you to Lyon to share knowledge and explore the future of measurement.

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The CFM, an association founded in 2002 with the support of the Ministry in charge of Industry, the LNE, the CETIAT, and STELLANTIS.

MONDAY 15

09.00 am – 10.30
WORKSHOP
MetriQs
Metrology for Quantum Technologies

11.00 – 12.30 pm
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Metrology for Quantum Technologies

WELCOME

OPENING SESSION

02.00 – 03.30
S1 Traceable thermometry: from fixed points to AI
S2 Leveraging the potential of DCC
ROUND TABLE Metrology for evidence-based Policy Making

04.00 – 05.30
S3 Advanced materials metrology
S4 Advances in low- and micro-flow metrology
S5 From data to decisions: trusted AI for metrology

WELCOME APÉRITIF
CELEBRATING 40 YEARS OF **EURAMET**

TUESDAY 16

WELCOME

09.00 am – 10.30
S6 DCC, an endless adoption phase?
S7 Quantum Metrology: from the lab to the real world
ROUND TABLE How can metrology meet the needs of the "New Defence"?

11.00 – 12.30 pm
PLENARY SESSION
NEW HORIZONS IN METROLOGY

01.30 – 03.00
ROUND TABLE Metrology for Quantum Computing
S8 New techniques for traceable temperature measurements
S9 Advancing the energy transition through gas flow metrology

03.30 – 05.00
POSTERS P1
Quantum technologies
Data Management
AI
Flow
Thermometry
Quality
Electricity
Industrial innovation

GALA EVENT
Silk & Velvet
LE GRAND RÉFECTOIRE

WEDNESDAY 17

WELCOME

09.00 am – 10.30
ROUND TABLE Metrology meets AI: confidence in the Age of Prediction
S10 Novel impedance metrology?
S11 Quality and Accreditation in industrial metrology

12.30 pm
POSTERS P2
Mechanics
Dimensional
Robotisation
Automatisation
Biology / Chemistry
Connectivity / Sensors
Uncertainty

01.30 – 03.00
S12 Next-Gen gas metrology for climate and energy
S13 Frontiers in traceability and measurement uncertainty
ROUND TABLE Is ISO 10012:2026 a new deal for Industrial Metrology?

03.30 – 05.00
S14 Metrology and Industry: partners for Innovation
S15 Sensing the future: from smart sensors to trusted data
S16 Digital metrology ecosystem: building trust

SIDE EVENT

THURSDAY 18

WELCOME

09.00 am – 10.30
S17 From electrical references to calibration
S18 Dimensional metrology: nano, macro and software
SHORT COURSE Food Metrology: from Farm to Fork

11.00 – 12.30 pm
S19 Challenges of robotisation and automation in metrology
S20 Metrology for health innovation
S21 Best for last: solar UV, gas flow, hydrogen, humidity

CLOSING & AWARDS

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CIM2027
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CONGRESS DATES

15 to 18 March 2027
Hosted at Global Industrie

HOTELS & TRANSPORTS

Details at www.cim-metrology.org
"Travel & Stay" section

FEES

Excluding 10% VAT
Prices & Registration: www.cim-metrology.org/en/fees/price-list

		BEST FEE Early Bird Until 20 Nov. 2026	Regular fee Until 17 Feb. 2027	Late fee Until the congress
Speakers	All days	569€	650€	750€
Attendees	1 day	569€	650€	750€
	2 days	735€	845€	975€
	4 days	895€	1025€	1185€
Academic pass Student, PhD or staff member at a university	2 days	300€	350€	400€
	4 days	400€	450€	500€

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- Gala Event (limited seats)
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- Onsite translation, congress proceedings

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